# Special Issue

# Simulation Modelling of Smart Grid Security and Dependability

### Message from the Guest Editors

Smart grid security and dependability is becoming one of the most important research areas of this decade. Despite significant progress being made in this field, new threats and vulnerabilities are continuously emerging as the smart grid is evolving by adapting and integrating new elements. The main aim of this Special Issue is to attract high-quality contributions addressing recent advancements in the field of smart grid simulation modelling of security and all dependability areas. Topics of interest include but are not limited to the following:

- Simulation modelling of smart grid security and dependability areas: availability, reliability, safety, confidentiality, integrity, and maintainability;
- Smart grid modelling using simulation and emulation techniques;
- Modelling of innovative approaches for smart grid control (e.g., software-defined networking);
- Modelling of smart grid networks threats, attacks, and vulnerabilities;
- Testing of modeled threats and vulnerabilities;
- Modelling of various elements of smart grid topology: control center, primary and secondary digital substations, and WANs with optional VPNs.

#### **Guest Editors**

Dr. Filip Holik

Prof. Dr. Sule Yildirim Yayilgan

Prof. Dr. Martin Gilje Jaatun

## Deadline for manuscript submissions

closed (1 November 2022)



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Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

### Editor-in-Chief

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